

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(713/182.ccls.) and database and (central adj directory) and authoriz\$5 and authenticat\$3 and (user adj role\$1) and (privilege\$1 with (local\$2 or (network adj node\$1)))	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/01 18:28
L2	0	(713/167.ccls.) and database and (central adj directory) and authoriz\$5 and authenticat\$3 and (user adj role\$1) and (privilege\$1 with (local\$2 or (network adj node\$1)))	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/01 18:28
L3	0	(713/166.ccls.) and database and (central adj directory) and authoriz\$5 and authenticat\$3 and (user adj role\$1) and (privilege\$1 with (local\$2 or (network adj node\$1)))	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/01 18:28
L4	0	(713/165.ccls.) and database and (central adj directory) and authoriz\$5 and authenticat\$3 and (user adj role\$1) and (privilege\$1 with (local\$2 or (network adj node\$1)))	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/01 18:28
L5	1	(707/9.ccls.) and database and (central adj directory) and authoriz\$5 and authenticat\$3 and (user adj role\$1) and (privilege\$1 with (local\$2 or (network adj node\$1)))	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/01 18:30
L6	1	database and (central adj directory) and authoriz\$5 and authenticat\$3 and (user adj role\$1) and (privilege\$1 with (local\$2 or (network adj node\$1)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/01/01 18:30

D6

IEEE Xplore® RELEASE 2.4

Welcome United States Patent and Trademark Office

Home | Login | Logout | Access Information | Alerts | Purchase History | Cart | Sitemap | Help

BROWSE SEARCH IEEE XPLORER GUIDE SUPPORT

Tue, 1 Jan 2008, 6:37:42 PM EST

Search Query Display

Select a search number (#) to:

- Add a query to the Search Query Display
- Combine search queries using AND, OR, or NOT
- Delete a search
- Run a search

Recent Search Queries

- #1 (central directory<and>local database network node)<and>local policy

Results

Help Contact Us Privacy & Security IEEE.org
 © Copyright 2007 IEEE - All Rights Reserved

Indexed by  Inspec®